

NSLS II Girder Profiling Activities

Tuesday, 11 September 2012 13:00 (25 minutes)

The ongoing NSLS II project requires ± 30 micron alignment accuracy for the 6 or 7 magnets in each girder assembly. The vibrating wire technique used to align magnets in one girder can achieve a couple of micron precision. However, the transportation and manner change of supporting will change the girder profile, hence the magnet alignment, to the extent of bigger than ± 50 micron. This paper will introduce the approach to be used to define, measure and recover the girder profile. Test result will be presented.

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